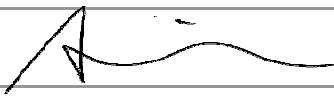


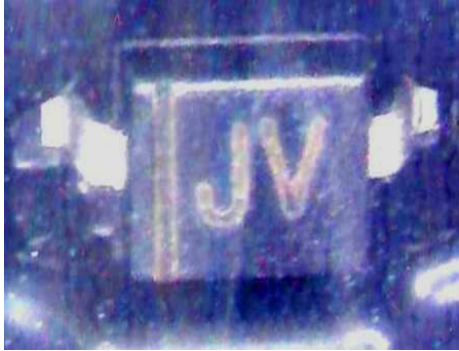

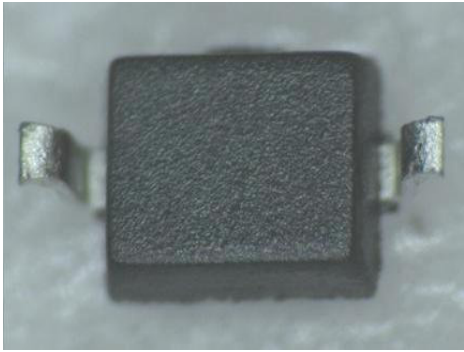
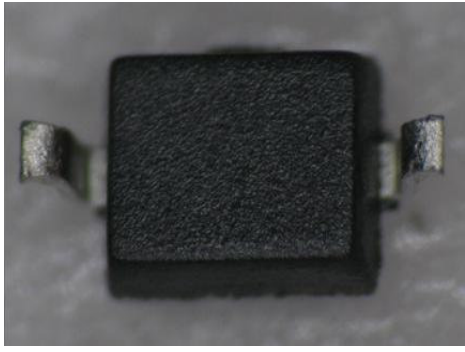


Product/Process Change Notification

PCN#	Effective Date	Issue Date
2016-05-03C-01	2016/8/3	2016/5/3
PCN Classification	Product Category	
Major	Schottky diode	
Subject		
Add assembly vendor.		
Affected Product(s)		
SCS751V-40		
Description of Change(s)		
In order to avoid shortage of the material, and enhance the speed of delivery, thus, we add a new assembly house.		
Content of Change(s)		
Assembly house and marking.		
Impact(s)		
None		
Attachment(s)		
Reliability Test Report.		

Approval		
Issued by	Alice Lai	e-mail: alice@secosgmbh.com
Development Engineer		Alice Lai
QA Manager		Peter Yang
General Manger		Mathew Liu
Customer Approval		
Customer's Comment		
Customer's Consent with Signature		

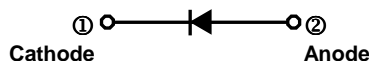
Exterior Comparison Chart	
Original	New
 <p>Top View</p>	 <p>Top View</p>
 <p>Back View</p>	 <p>Back View</p>

RoHS Compliant Product
A suffix of "-C" specifies halogen & lead-free

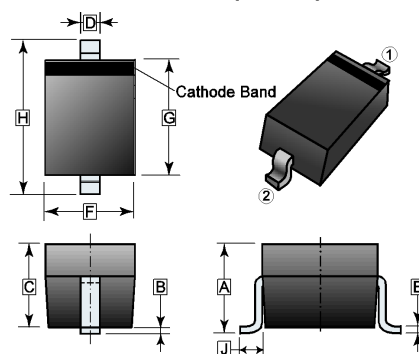
FEATURES

- RoHS compliant product
- Small surface mounting type
- Low reverse current and low forward voltage
- High reliability
- High speed switching

MARKING



SOD-323(SC-76)



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	1.05	REF.	F	1.15	1.45
B	0.20	REF.	G	1.6	1.8
C	0.80	1.00	H	2.55	2.75
D	0.25	0.40	J	0.475 REF.	
E	0.080	0.180			

MAXIMUM RATINGS AND ELECTRICAL CHARACTERISTICS

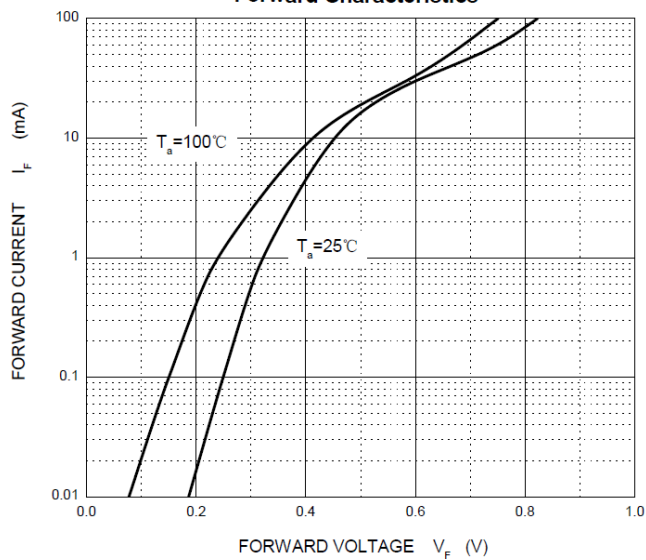
(Rating 25°C ambient temperature unless otherwise specified. Single phase half wave, 60Hz, resistive or inductive load.

For capacitive load, de-rate current by 20%.)

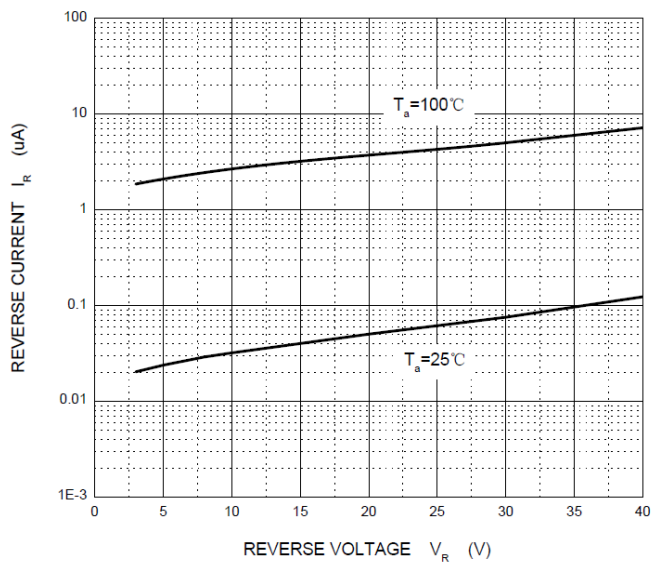
Parameter	Symbol	Rating	Unit
Maximum Recurrent Peak Reverse Voltage	V_{RRM}	40	V
DC Reverse Voltage	V_R	30	V
Maximum Instantaneous Forward Voltage@ $I_F=1mA$	V_F	0.37	V
Maximum DC Reverse Current@ $V_R=30V$	I_R	0.5	μA
Mean Rectifying Current	I_o	0.03	A
Peak Forward Current@ 8.3ms single half sine-wave superimposed on rated Load	I_{FSM}	200	mA
Typical Capacitance between terminals@ $V_R=1V, f=1MHz$	C_T	2	pF
Power Dissipation	P_D	200	mW
Thermal Resistance from Junction to Ambient	$R_{\theta JA}$	500	$^{\circ}C / W$
Operating Junction and Storage Temperature Range	T_J, T_{STG}	125, -55~150	$^{\circ}C$

CHARACTERISTIC CURVES

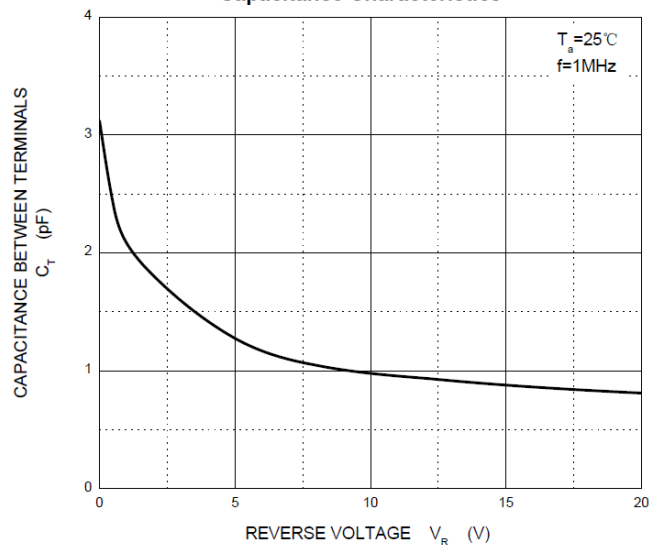
Forward Characteristics



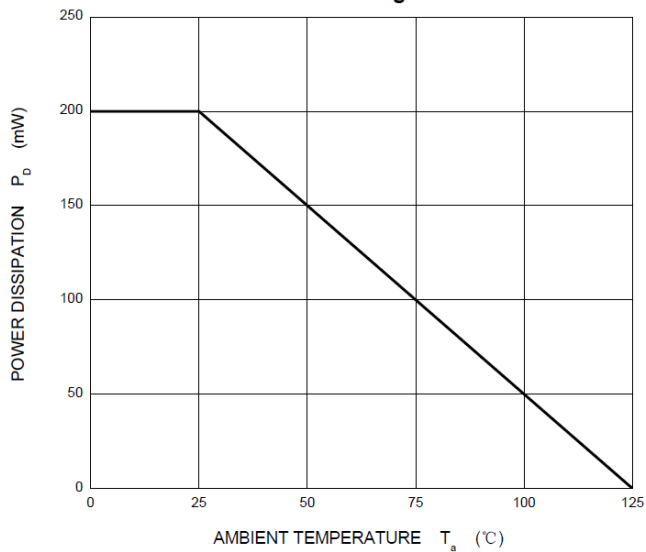
Reverse Characteristics



Capacitance Characteristics



Power Derating Curve





Reliability Testing Summary Report

Date: 2016/04/29

Document No.: SI16 -04- 11

Test Item	P/N	Test Condition	(LTPD)	Sample Numbers	Allow Fall Numbers	Fall Numbers	Result
HTRB High Temp Reverse Bias	SCS751V-40	100 ± 5°C, 80% VR, T = 1000hrs		77	0	0	ACC
HTSL High Temperature Storage Life	SCS751V-40	150°C, T = 1000 hrs		77	0	0	ACC
PCT Pressure Cooker Test	SCS751V-40	121°C, 29.7PSIG, 168 hrs		77	0	0	ACC
TCT Temperature Cycle Test	SCS751V-40	-55°C/30min, 150°C/30min, For 1000 Cycle		77	0	0	ACC
THT High Temperature High Humidity Test	SCS751V-40	85 ± 2°C, RH=85±5%, 1000 hrs		77	0	0	ACC
H3TRB High Temper High Humidity Reverse Bies Test	SCS751V-40	85 ± 2°C, RH=85±5%, 80% VR, 1000 hrs		77	0	0	ACC
Solderability	SCS751V-40	245 ± 5°C, 5Sec the inspected area of each lead must have 95% solder coverage minimum		10	0	0	ACC

Judgment:

qualified unqualified

Testing Start Date: 2016.03.01 Testing End Date: 2016.04.29

Tester: King Huang Approval: Peter Yang



Electrical Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: 25°C

Test Date: 2016.03.01

Test Standard : Specifications

Operator: Leo Hsia

Test Result: PASS

No	VF	VB	IR
1	336.3mV	47.15V	109.6nA
2	336.0mV	47.66V	104.8nA
3	337.1mV	49.07V	104.6nA
4	335.4mV	48.44V	111.3nA
5	337.3mV	48.10V	108.7nA
6	335.7mV	48.22V	105.2nA
7	335.7mV	47.26V	112.4nA
8	337.2mV	48.53V	112.6nA
9	335.3mV	47.83V	111.9nA
10	335.7mV	46.93V	112.5nA
11	335.5mV	48.41V	107.7nA
12	336.1mV	47.29V	109.4nA
13	334.8mV	49.44V	110.2nA
14	335.7mV	46.99V	111.0nA
15	337.1mV	47.77V	109.5nA
16	336.5mV	48.67V	106.6nA
17	334.8mV	49.03V	111.8nA
18	335.6mV	48.65V	110.2nA
19	334.6mV	47.71V	111.3nA
20	335.6mV	48.35V	106.4nA
21	335.3mV	49.15V	109.3nA
22	336.1mV	48.26V	112.1nA
23	336.5mV	49.39V	108.9nA
24	336.2mV	48.29V	110.7nA
25	336.7mV	49.06V	105.9nA
26	334.6mV	49.20V	112.4nA
27	334.8mV	47.11V	112.6nA
28	337.2mV	49.65V	107.6nA
29	335.3mV	48.70V	106.1nA
30	337.3mV	48.84V	107.6nA
31	335.4mV	47.10V	107.9nA



Electrical Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: 25°C

Test Date: 2016.03.01

Test Standard : Specifications

Operator: Leo Hsia

Test Result: PASS

No	VF	VB	IR
32	337.4mV	48.01V	109.1nA
33	335.1mV	48.20V	111.3nA
34	337.1mV	48.12V	112.1nA
35	335.5mV	47.78V	110.2nA
36	335.8mV	48.36V	112.6nA
37	335.8mV	47.16V	111.0nA
38	335.0mV	47.06V	109.1nA
39	336.4mV	49.61V	106.8nA
40	335.8mV	49.31V	111.4nA
41	337.0mV	46.99V	109.9nA
42	335.5mV	49.63V	108.4nA
43	335.7mV	47.84V	106.9nA
44	334.6mV	48.57V	107.7nA
45	337.1mV	48.91V	110.1nA
46	336.6mV	47.46V	111.1nA
47	334.6mV	49.05V	111.1nA
48	336.7mV	49.22V	109.4nA
49	334.9mV	49.48V	107.2nA
50	335.0mV	48.93V	106.7nA
51	335.9mV	47.34V	105.1nA
52	336.9mV	48.33V	107.6nA
53	335.7mV	48.37V	110.7nA
54	335.4mV	48.64V	106.3nA
55	336.1mV	48.45V	106.0nA
56	335.5mV	49.39V	111.0nA
57	335.6mV	48.04V	112.5nA
58	334.9mV	47.01V	108.8nA
59	337.3mV	49.22V	108.7nA
60	336.0mV	47.33V	109.4nA
61	335.8mV	47.13V	112.2nA
62	337.2mV	47.51V	110.1nA



Electrical Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: 25°C

Test Date: 2016.03.01

Test Standard : Specifications

Operator: Leo Hsia

Test Result: PASS

No	VF	VB	IR
63	335.0mV	49.26V	104.8nA
64	335.6mV	47.41V	110.1nA
65	335.2mV	47.92V	106.2nA
66	336.4mV	47.23V	108.2nA
67	336.5mV	49.32V	105.1nA
68	334.8mV	48.27V	109.3nA
69	337.1mV	49.62V	111.8nA
70	334.7mV	48.14V	105.2nA
71	335.0mV	48.05V	106.3nA
72	334.7mV	49.00V	105.3nA
73	335.1mV	47.76V	111.6nA
74	336.6mV	46.95V	104.8nA
75	335.8mV	48.59V	112.2nA
76	334.6mV	48.58V	104.9nA
77	337.3mV	47.87V	107.5nA

Made By: King Huang

Approval: Peter Yang



High Temperature Reverse Bias Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: 100 ± 5°C, 80% VR, T = 1000 hrs

Test Date: 2016.03.01 ~ 2016.04.13

Test Standard : JESD22 STANDARD Method-A108

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF	VB	IR	VF	VB	IR
1	336.6mV	49.01V	112.0nA	337.3mV	48.42V	105.2nA
2	335.7mV	49.36V	112.5nA	335.1mV	47.80V	108.6nA
3	337.4mV	49.10V	105.5nA	336.9mV	47.86V	107.5nA
4	336.1mV	47.25V	111.7nA	336.3mV	48.42V	105.4nA
5	335.4mV	47.39V	109.7nA	335.1mV	48.97V	106.3nA
6	335.4mV	48.62V	112.1nA	336.9mV	47.06V	111.6nA
7	337.0mV	47.26V	109.0nA	337.0mV	49.28V	106.0nA
8	335.8mV	48.74V	112.1nA	335.4mV	47.69V	108.0nA
9	337.2mV	48.76V	106.2nA	336.8mV	47.78V	111.7nA
10	334.7mV	48.77V	107.8nA	336.6mV	48.22V	105.9nA
11	336.8mV	47.13V	107.2nA	336.3mV	49.07V	112.4nA
12	337.4mV	48.00V	106.3nA	336.5mV	48.51V	110.9nA
13	336.3mV	47.50V	106.9nA	336.2mV	48.43V	107.2nA
14	335.1mV	46.96V	106.8nA	334.6mV	48.32V	109.8nA
15	335.3mV	48.73V	110.3nA	335.6mV	48.11V	106.2nA
16	335.4mV	47.36V	111.6nA	335.8mV	48.58V	106.4nA
17	337.0mV	48.58V	108.6nA	336.3mV	48.05V	112.2nA
18	334.8mV	49.63V	106.5nA	335.4mV	49.21V	107.7nA
19	335.6mV	48.23V	109.3nA	335.8mV	48.86V	105.1nA
20	336.5mV	47.18V	111.3nA	336.3mV	48.09V	108.7nA
21	335.3mV	48.56V	110.3nA	336.7mV	48.23V	111.7nA
22	335.4mV	48.97V	105.2nA	336.6mV	49.24V	111.4nA
23	336.7mV	47.90V	107.0nA	336.4mV	47.16V	109.4nA
24	334.5mV	48.12V	106.9nA	335.5mV	49.65V	105.0nA
25	337.1mV	48.36V	105.6nA	335.6mV	49.49V	104.8nA
26	334.6mV	48.83V	107.4nA	335.1mV	48.72V	108.8nA
27	334.9mV	48.10V	112.2nA	336.3mV	49.30V	111.7nA
28	337.5mV	48.68V	105.0nA	337.2mV	47.49V	111.1nA
29	334.7mV	47.73V	109.2nA	336.1mV	48.49V	105.1nA
30	335.7mV	46.94V	107.4nA	334.6mV	48.37V	106.5nA



High Temperature Reverse Bias Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: 100 ± 5°C, 80% VR, T = 1000 hrs

Test Date: 2016.03.01 ~ 2016.04.13

Test Standard : JESD22 STANDARD Method-A108

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF	VB	IR	VF	VB	IR
31	335.1mV	47.88V	112.1nA	336.1mV	47.18V	107.3nA
32	336.0mV	49.23V	110.2nA	334.7mV	48.76V	106.0nA
33	336.1mV	49.16V	105.8nA	337.0mV	48.34V	106.0nA
34	337.2mV	47.37V	108.2nA	335.4mV	49.32V	106.2nA
35	337.0mV	48.18V	112.3nA	337.0mV	47.03V	110.8nA
36	335.4mV	49.36V	107.2nA	334.8mV	48.75V	104.9nA
37	337.3mV	48.29V	111.5nA	335.1mV	49.05V	105.8nA
38	334.6mV	47.91V	108.8nA	335.4mV	48.99V	106.6nA
39	337.0mV	47.09V	105.8nA	335.6mV	48.02V	108.9nA
40	337.2mV	46.99V	104.8nA	335.9mV	49.27V	107.8nA
41	337.0mV	47.96V	105.7nA	336.9mV	48.30V	106.4nA
42	335.6mV	47.89V	108.6nA	336.6mV	47.51V	110.2nA
43	336.2mV	47.54V	110.0nA	335.9mV	47.86V	106.2nA
44	334.7mV	46.91V	108.8nA	337.1mV	49.64V	106.6nA
45	336.0mV	49.41V	105.9nA	336.4mV	49.13V	108.2nA
46	335.9mV	47.29V	112.6nA	337.3mV	48.09V	105.8nA
47	337.3mV	47.22V	110.6nA	335.7mV	47.38V	112.5nA
48	336.8mV	47.94V	108.7nA	335.2mV	47.58V	110.3nA
49	336.3mV	48.11V	107.8nA	337.1mV	48.13V	107.5nA
50	335.9mV	47.02V	111.6nA	337.1mV	47.24V	109.7nA
51	335.8mV	48.91V	105.5nA	336.5mV	48.96V	111.2nA
52	337.0mV	49.53V	106.2nA	335.8mV	47.11V	112.6nA
53	335.8mV	48.27V	112.5nA	336.6mV	48.38V	108.0nA
54	335.3mV	47.12V	109.2nA	334.7mV	46.96V	112.4nA
55	334.9mV	47.42V	111.2nA	337.3mV	49.35V	106.8nA
56	337.2mV	49.62V	109.8nA	334.6mV	48.50V	111.8nA
57	336.6mV	48.50V	107.0nA	335.5mV	48.03V	108.8nA
58	336.5mV	48.10V	109.1nA	336.6mV	49.35V	111.3nA
59	335.0mV	48.41V	106.8nA	337.1mV	48.82V	110.2nA
60	334.5mV	48.02V	108.0nA	337.0mV	48.19V	111.7nA



High Temperature Reverse Bias Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: 100 ± 5°C, 80% VR, T = 1000 hrs

Test Date: 2016.03.01 ~ 2016.04.13

Test Standard : JESD22 STANDARD Method-A108

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF	VB	IR	VF	VB	IR
61	336.6mV	47.32V	105.7nA	335.8mV	48.47V	108.9nA
62	335.9mV	48.61V	111.6nA	337.3mV	48.55V	108.3nA
63	337.4mV	47.80V	107.2nA	336.8mV	49.47V	108.3nA
64	337.4mV	47.36V	110.2nA	336.8mV	47.95V	110.8nA
65	336.1mV	47.03V	110.2nA	337.5mV	48.09V	110.3nA
66	335.3mV	49.15V	109.4nA	336.9mV	47.99V	106.2nA
67	336.3mV	49.30V	109.8nA	335.5mV	47.61V	110.7nA
68	336.0mV	48.59V	105.7nA	335.5mV	46.89V	110.0nA
69	336.3mV	47.49V	106.1nA	336.8mV	47.72V	107.3nA
70	335.9mV	47.01V	105.7nA	334.8mV	47.65V	111.6nA
71	335.4mV	47.25V	105.7nA	336.4mV	49.25V	110.0nA
72	337.3mV	47.07V	107.7nA	335.9mV	47.08V	106.2nA
73	336.4mV	48.53V	105.6nA	336.8mV	48.50V	108.5nA
74	336.7mV	48.67V	112.5nA	335.0mV	49.34V	109.5nA
75	337.4mV	48.82V	105.8nA	336.7mV	49.32V	106.9nA
76	336.5mV	47.50V	112.6nA	334.7mV	48.83V	108.8nA
77	335.5mV	48.06V	107.7nA	336.3mV	47.93V	105.6nA

Made By: King Huang

Approval: Peter Yang



High Temperature Storage Life Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: 150°C, 1000Hrs

Test Date: 2016.03.01 ~ 2016.04.13

Test Standard : JESD22 STANDARD Method-A103

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF	VB	IR	VF	VB	IR
1	336.7mV	48.41V	108.3nA	335.3mV	49.46V	110.4nA
2	334.6mV	48.29V	104.7nA	337.3mV	48.10V	107.7nA
3	335.9mV	48.44V	110.4nA	335.4mV	48.37V	109.7nA
4	337.2mV	47.58V	106.5nA	335.5mV	48.16V	110.7nA
5	336.8mV	49.29V	109.3nA	334.6mV	49.00V	111.3nA
6	336.1mV	49.08V	105.1nA	335.5mV	47.65V	110.5nA
7	335.9mV	49.40V	112.2nA	336.5mV	48.57V	104.9nA
8	337.0mV	48.63V	105.3nA	335.6mV	49.17V	109.8nA
9	337.2mV	47.16V	105.2nA	337.2mV	48.99V	111.0nA
10	337.2mV	46.89V	109.9nA	337.2mV	48.06V	112.0nA
11	335.9mV	47.13V	111.1nA	335.8mV	49.22V	111.8nA
12	335.4mV	48.29V	107.8nA	336.4mV	48.60V	107.4nA
13	335.2mV	47.18V	106.3nA	336.1mV	47.40V	112.5nA
14	337.1mV	47.74V	105.5nA	336.5mV	48.70V	112.0nA
15	335.7mV	48.65V	107.2nA	337.1mV	48.28V	106.9nA
16	337.1mV	47.26V	105.5nA	335.7mV	49.37V	105.5nA
17	334.8mV	48.57V	112.5nA	335.0mV	49.60V	107.3nA
18	335.1mV	48.43V	104.8nA	334.6mV	48.60V	110.0nA
19	335.0mV	48.24V	105.3nA	336.9mV	47.53V	110.4nA
20	334.9mV	47.80V	107.8nA	336.2mV	49.33V	110.0nA
21	334.8mV	48.92V	107.6nA	335.7mV	47.50V	109.6nA
22	335.4mV	48.15V	109.1nA	337.0mV	48.22V	105.8nA
23	335.5mV	47.18V	106.5nA	335.5mV	49.50V	112.6nA
24	336.8mV	49.27V	106.9nA	336.9mV	49.39V	107.5nA
25	335.0mV	48.71V	106.9nA	335.3mV	49.42V	112.0nA
26	335.9mV	47.55V	105.7nA	336.2mV	49.33V	105.2nA
27	337.3mV	46.90V	107.7nA	335.5mV	47.82V	111.8nA
28	337.1mV	47.80V	111.9nA	335.7mV	48.52V	107.3nA
29	337.3mV	47.90V	107.6nA	335.3mV	49.46V	109.8nA
30	335.8mV	48.43V	108.6nA	335.5mV	47.72V	108.9nA



High Temperature Storage Life Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: 150°C, 1000Hrs

Test Date: 2016.03.01 ~ 2016.04.13

Test Standard : JESD22 STANDARD Method-A103

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF	VB	IR	VF	VB	IR
31	337.0mV	47.06V	112.2nA	337.0mV	49.27V	105.6nA
32	336.7mV	49.08V	109.9nA	335.6mV	49.44V	109.8nA
33	336.3mV	47.05V	106.7nA	335.1mV	49.08V	109.7nA
34	335.7mV	47.80V	107.1nA	336.3mV	47.72V	107.8nA
35	335.4mV	48.54V	105.0nA	337.2mV	47.02V	111.3nA
36	336.8mV	47.18V	109.8nA	336.4mV	48.63V	107.8nA
37	335.2mV	49.59V	109.7nA	337.0mV	48.68V	106.9nA
38	335.8mV	47.07V	111.2nA	335.3mV	48.45V	107.7nA
39	336.2mV	47.70V	110.6nA	336.6mV	48.77V	110.8nA
40	337.1mV	46.96V	106.6nA	334.6mV	48.67V	110.2nA
41	337.1mV	49.54V	105.6nA	335.8mV	49.33V	104.7nA
42	337.1mV	48.18V	107.7nA	337.2mV	48.07V	105.9nA
43	337.2mV	48.53V	107.8nA	335.9mV	47.92V	111.1nA
44	336.2mV	47.03V	104.6nA	336.9mV	47.20V	105.5nA
45	336.2mV	48.98V	109.7nA	336.1mV	48.71V	111.2nA
46	337.0mV	47.67V	108.2nA	335.0mV	47.33V	109.9nA
47	334.9mV	48.35V	108.2nA	335.0mV	46.97V	109.7nA
48	334.7mV	49.24V	111.9nA	336.0mV	49.23V	105.5nA
49	335.9mV	49.62V	105.2nA	336.9mV	47.35V	109.4nA
50	335.6mV	49.33V	110.3nA	336.9mV	48.38V	109.3nA
51	337.3mV	48.71V	109.1nA	335.3mV	47.27V	106.7nA
52	335.9mV	47.39V	105.6nA	337.2mV	47.22V	109.1nA
53	336.2mV	47.80V	107.3nA	336.8mV	49.29V	105.7nA
54	334.8mV	48.99V	106.2nA	336.3mV	48.90V	105.8nA
55	336.9mV	49.28V	107.8nA	336.2mV	47.85V	106.7nA
56	335.7mV	47.08V	111.8nA	337.1mV	49.37V	106.5nA
57	335.5mV	46.91V	111.3nA	334.6mV	48.75V	110.9nA
58	336.4mV	47.55V	109.7nA	335.1mV	49.52V	108.3nA
59	336.8mV	47.09V	111.7nA	334.9mV	48.81V	105.1nA
60	336.2mV	48.78V	105.4nA	335.8mV	47.61V	106.8nA



High Temperature Storage Life Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: 150°C, 1000Hrs

Test Date: 2016.03.01 ~ 2016.04.13

Test Standard : JESD22 STANDARD Method-A103

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF	VB	IR	VF	VB	IR
61	336.2mV	49.58V	111.1nA	336.0mV	47.45V	109.9nA
62	337.4mV	46.99V	111.9nA	337.4mV	49.64V	111.4nA
63	335.6mV	49.15V	105.9nA	335.5mV	49.00V	107.0nA
64	335.8mV	47.32V	109.3nA	337.4mV	48.51V	112.1nA
65	335.9mV	49.04V	105.0nA	335.5mV	49.25V	111.9nA
66	336.9mV	49.12V	106.0nA	337.0mV	48.30V	107.9nA
67	334.5mV	47.21V	105.9nA	335.4mV	49.41V	107.5nA
68	334.9mV	48.19V	110.5nA	336.9mV	48.88V	110.0nA
69	335.8mV	48.00V	106.9nA	335.6mV	48.64V	109.8nA
70	336.6mV	47.95V	106.3nA	335.2mV	48.32V	111.6nA
71	335.2mV	46.95V	105.4nA	337.1mV	48.99V	106.2nA
72	335.6mV	46.92V	108.5nA	337.3mV	48.13V	105.7nA
73	335.6mV	48.03V	104.7nA	335.3mV	49.59V	106.5nA
74	334.8mV	46.87V	104.8nA	335.9mV	47.95V	110.3nA
75	335.2mV	49.55V	108.4nA	336.9mV	47.97V	111.5nA
76	334.9mV	49.17V	106.2nA	334.9mV	49.08V	107.4nA
77	335.8mV	48.25V	110.2nA	334.9mV	47.28V	111.0nA

Made By: King Huang

Approval: Peter Yang



SeCoS Corporation

Pressure Cooker Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: 121°C, 100%RH, 29.7PSIG, 168Hrs

Test Date: 2016.03.01 ~ 2016.03.09

Test Standard : JESD22 STANDARD Method-A102

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF	VB	IR	VF	VB	IR
1	334.9mV	47.42V	111.6nA	337.2mV	48.98V	108.0nA
2	336.5mV	47.82V	108.3nA	337.1mV	48.67V	105.1nA
3	335.6mV	48.72V	110.5nA	336.9mV	48.02V	104.8nA
4	335.4mV	49.43V	111.6nA	334.8mV	48.70V	106.8nA
5	335.5mV	49.15V	109.8nA	337.4mV	47.76V	105.7nA
6	336.2mV	47.48V	110.7nA	336.5mV	49.46V	109.5nA
7	337.0mV	46.90V	106.0nA	334.8mV	49.10V	109.1nA
8	336.6mV	47.19V	110.3nA	336.1mV	49.24V	104.7nA
9	335.8mV	47.40V	110.3nA	335.1mV	49.07V	105.9nA
10	336.3mV	48.12V	107.6nA	336.1mV	49.52V	110.3nA
11	337.2mV	48.35V	109.0nA	334.7mV	49.44V	105.3nA
12	335.2mV	47.33V	111.2nA	336.6mV	47.91V	110.7nA
13	334.8mV	48.47V	108.5nA	336.9mV	48.94V	109.6nA
14	336.6mV	48.64V	110.2nA	335.3mV	48.45V	106.7nA
15	337.0mV	47.06V	104.9nA	336.6mV	46.88V	110.8nA
16	336.6mV	49.26V	112.4nA	336.6mV	48.33V	112.4nA
17	336.1mV	47.54V	112.6nA	337.5mV	48.93V	108.8nA
18	334.9mV	47.86V	105.2nA	336.3mV	48.81V	110.7nA
19	335.5mV	47.60V	110.7nA	337.3mV	49.27V	107.0nA
20	336.4mV	48.11V	107.1nA	337.2mV	49.36V	109.3nA
21	336.4mV	48.30V	112.3nA	334.7mV	47.36V	111.7nA
22	336.1mV	47.79V	105.2nA	334.8mV	47.82V	112.0nA
23	335.5mV	47.23V	111.2nA	335.9mV	48.31V	106.9nA
24	335.8mV	48.63V	106.5nA	336.5mV	49.24V	112.2nA
25	336.5mV	49.36V	112.6nA	336.6mV	48.34V	111.2nA
26	335.6mV	47.78V	104.6nA	336.4mV	46.90V	111.8nA
27	335.4mV	49.51V	111.9nA	336.2mV	47.71V	108.2nA
28	336.5mV	47.58V	106.5nA	336.4mV	48.66V	108.2nA
29	336.0mV	48.67V	106.1nA	337.5mV	47.94V	110.0nA
30	336.7mV	49.51V	109.2nA	335.9mV	48.50V	106.3nA



SeCoS Corporation

Pressure Cooker Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: 121°C, 100%RH, 29.7PSIG, 168Hrs

Test Date: 2016.03.01 ~ 2016.03.09

Test Standard : JESD22 STANDARD Method-A102

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF	VB	IR	VF	VB	IR
31	334.7mV	48.44V	106.0nA	336.7mV	47.32V	108.0nA
32	335.7mV	47.15V	105.8nA	337.3mV	47.47V	107.5nA
33	335.5mV	47.23V	112.2nA	335.5mV	48.95V	110.4nA
34	337.2mV	49.14V	106.7nA	334.7mV	48.05V	106.9nA
35	337.4mV	47.17V	108.6nA	337.3mV	47.28V	109.6nA
36	337.0mV	49.44V	108.3nA	337.0mV	49.34V	110.1nA
37	337.2mV	46.91V	107.3nA	337.4mV	48.14V	106.9nA
38	334.8mV	49.03V	105.9nA	337.3mV	47.78V	106.5nA
39	334.6mV	48.03V	109.9nA	334.7mV	46.86V	108.7nA
40	336.0mV	47.17V	108.1nA	334.5mV	48.94V	111.7nA
41	336.6mV	48.14V	108.8nA	337.1mV	48.43V	110.1nA
42	334.9mV	47.47V	105.3nA	337.0mV	47.77V	112.4nA
43	336.3mV	47.28V	108.6nA	337.5mV	48.57V	108.8nA
44	336.2mV	47.98V	105.7nA	337.2mV	47.10V	106.1nA
45	335.4mV	49.64V	107.1nA	335.1mV	47.66V	105.5nA
46	335.6mV	48.42V	104.7nA	336.5mV	47.16V	106.2nA
47	335.9mV	48.72V	108.3nA	334.8mV	47.71V	109.4nA
48	336.4mV	47.70V	111.5nA	334.5mV	48.97V	108.4nA
49	336.7mV	48.55V	111.3nA	334.6mV	48.96V	106.8nA
50	336.6mV	48.63V	106.7nA	336.0mV	47.92V	107.3nA
51	335.4mV	47.28V	107.4nA	336.6mV	48.67V	106.7nA
52	335.4mV	47.53V	106.1nA	335.4mV	47.49V	110.5nA
53	334.8mV	47.59V	109.5nA	335.7mV	49.30V	111.7nA
54	336.1mV	47.65V	108.3nA	336.8mV	49.14V	112.3nA
55	336.5mV	49.44V	105.5nA	337.0mV	48.66V	106.7nA
56	335.8mV	47.00V	107.1nA	335.0mV	47.83V	109.8nA
57	335.5mV	48.07V	105.5nA	336.3mV	48.98V	108.7nA
58	335.2mV	48.52V	106.4nA	335.7mV	47.88V	105.1nA
59	336.4mV	48.11V	110.0nA	335.3mV	48.46V	108.7nA
60	337.1mV	49.11V	108.4nA	337.0mV	48.13V	110.7nA



SeCoS Corporation

Pressure Cooker Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: 121°C, 100%RH, 29.7PSIG, 168Hrs

Test Date: 2016.03.01 ~ 2016.03.09

Test Standard : JESD22 STANDARD Method-A102

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF	VB	IR	VF	VB	IR
61	337.3mV	48.09V	110.9nA	336.8mV	47.79V	111.2nA
62	337.4mV	49.53V	109.7nA	335.0mV	48.65V	108.0nA
63	335.3mV	48.41V	109.8nA	336.8mV	47.93V	106.3nA
64	336.8mV	48.38V	110.1nA	336.6mV	49.09V	111.0nA
65	337.5mV	49.34V	112.0nA	334.6mV	48.70V	105.1nA
66	336.4mV	48.38V	106.1nA	334.7mV	49.02V	105.2nA
67	336.4mV	48.89V	110.7nA	336.3mV	48.14V	107.3nA
68	336.7mV	49.25V	109.5nA	336.5mV	48.80V	111.6nA
69	334.5mV	47.62V	111.2nA	336.4mV	48.67V	106.1nA
70	335.6mV	48.01V	109.3nA	335.6mV	47.24V	108.9nA
71	334.5mV	47.08V	110.3nA	335.4mV	48.06V	111.6nA
72	336.8mV	47.84V	107.5nA	336.8mV	48.91V	110.0nA
73	334.9mV	48.92V	108.8nA	336.8mV	48.43V	109.7nA
74	335.9mV	47.87V	110.2nA	336.3mV	49.24V	105.4nA
75	335.6mV	48.89V	106.3nA	337.5mV	47.06V	111.1nA
76	336.2mV	48.56V	108.0nA	334.8mV	49.30V	111.6nA
77	334.6mV	47.25V	109.8nA	336.9mV	48.48V	112.1nA

Made By: King Huang

Approval: Peter Yang



SeCoS Corporation

Temperature Cycle Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: -55°C/30min, 150°C/30min, for1000 Cycle

Test Date: 2016.03.02 ~ 2016.04.27

Test Standard : JESD22 STANDARD Method-A104

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF	VB	IR	VF	VB	IR
1	334.6mV	47.64V	107.5nA	335.1mV	49.03V	109.1nA
2	336.3mV	48.00V	109.7nA	336.0mV	49.10V	107.9nA
3	335.1mV	47.40V	108.3nA	336.8mV	46.99V	108.7nA
4	335.6mV	48.15V	105.7nA	336.6mV	47.09V	109.1nA
5	336.8mV	48.43V	108.5nA	337.4mV	49.34V	111.7nA
6	336.5mV	46.95V	109.6nA	335.6mV	49.61V	107.1nA
7	335.6mV	49.52V	105.7nA	335.9mV	48.00V	107.5nA
8	336.3mV	49.37V	107.0nA	336.4mV	48.72V	110.1nA
9	335.9mV	48.31V	111.6nA	336.6mV	47.45V	108.3nA
10	335.0mV	48.58V	107.4nA	334.5mV	47.33V	110.0nA
11	334.7mV	48.75V	107.6nA	337.1mV	46.92V	108.6nA
12	335.3mV	47.40V	106.3nA	336.3mV	47.15V	107.1nA
13	336.7mV	47.89V	109.0nA	337.0mV	48.20V	109.4nA
14	337.1mV	49.28V	109.6nA	336.7mV	49.53V	108.2nA
15	337.4mV	47.13V	109.2nA	337.0mV	48.79V	109.2nA
16	335.0mV	48.43V	109.3nA	335.1mV	48.52V	108.0nA
17	336.1mV	48.76V	107.9nA	336.9mV	48.12V	105.6nA
18	336.3mV	49.63V	105.3nA	337.3mV	47.59V	106.2nA
19	335.4mV	47.09V	112.3nA	335.2mV	48.14V	107.1nA
20	335.6mV	48.10V	105.7nA	334.7mV	47.34V	107.8nA
21	334.9mV	48.87V	112.5nA	336.9mV	47.81V	108.5nA
22	337.1mV	48.01V	106.8nA	336.8mV	49.05V	106.3nA
23	335.0mV	49.51V	104.7nA	335.2mV	47.30V	107.2nA
24	335.3mV	47.74V	109.8nA	337.1mV	47.49V	111.6nA
25	336.9mV	49.07V	110.8nA	335.9mV	48.47V	110.0nA
26	335.5mV	48.98V	108.9nA	337.3mV	48.42V	109.6nA
27	334.6mV	49.44V	112.0nA	336.5mV	47.81V	112.1nA
28	334.5mV	49.24V	112.0nA	335.5mV	48.69V	108.8nA
29	334.6mV	47.28V	111.9nA	334.6mV	48.75V	108.2nA
30	337.2mV	48.53V	110.9nA	335.9mV	49.24V	109.0nA



SeCoS Corporation

Temperature Cycle Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: -55°C/30min, 150°C/30min, for1000 Cycle

Test Date: 2016.03.02 ~ 2016.04.27

Test Standard : JESD22 STANDARD Method-A104

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF	VB	IR	VF	VB	IR
31	336.3mV	48.67V	109.0nA	337.1mV	49.04V	108.7nA
32	336.9mV	48.87V	110.2nA	336.3mV	48.60V	112.1nA
33	334.7mV	47.84V	109.5nA	337.3mV	47.80V	110.3nA
34	337.3mV	47.67V	107.9nA	336.6mV	48.13V	112.1nA
35	337.2mV	47.60V	112.3nA	335.6mV	48.43V	112.2nA
36	336.2mV	47.69V	107.4nA	336.6mV	48.47V	107.1nA
37	336.1mV	48.76V	106.3nA	337.2mV	47.71V	106.6nA
38	334.8mV	47.29V	111.3nA	334.6mV	48.54V	107.0nA
39	334.6mV	47.73V	109.6nA	336.8mV	49.48V	107.4nA
40	337.1mV	49.05V	111.0nA	337.3mV	49.05V	111.7nA
41	335.9mV	49.44V	105.5nA	335.1mV	47.88V	110.7nA
42	335.3mV	47.29V	110.0nA	337.1mV	47.87V	105.6nA
43	336.1mV	49.08V	111.5nA	336.3mV	47.10V	108.2nA
44	334.7mV	48.15V	112.5nA	335.1mV	48.88V	110.1nA
45	334.7mV	48.32V	110.0nA	337.3mV	49.38V	107.8nA
46	336.5mV	47.67V	110.9nA	335.1mV	48.96V	106.9nA
47	334.9mV	47.60V	110.4nA	337.0mV	47.66V	107.9nA
48	335.6mV	47.64V	108.7nA	335.6mV	48.01V	106.0nA
49	336.1mV	47.95V	106.3nA	337.4mV	47.55V	105.1nA
50	336.7mV	47.11V	112.3nA	337.4mV	48.79V	108.0nA
51	337.4mV	47.28V	108.4nA	335.9mV	47.15V	111.0nA
52	336.0mV	47.06V	109.5nA	337.5mV	49.06V	108.2nA
53	334.8mV	48.15V	106.1nA	335.0mV	48.80V	109.5nA
54	336.3mV	47.80V	107.6nA	337.3mV	47.27V	109.8nA
55	336.5mV	47.26V	107.0nA	335.5mV	49.41V	106.1nA
56	336.5mV	47.81V	112.2nA	336.5mV	49.03V	109.5nA
57	334.8mV	48.08V	109.3nA	335.9mV	48.65V	105.6nA
58	334.8mV	46.93V	108.1nA	336.1mV	48.83V	111.7nA
59	336.4mV	47.66V	106.0nA	335.5mV	49.42V	110.6nA
60	335.0mV	47.86V	104.7nA	336.9mV	48.33V	104.6nA



SeCoS Corporation

Temperature Cycle Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: -55°C/30min, 150°C/30min, for1000 Cycle

Test Date: 2016.03.02 ~ 2016.04.27

Test Standard : JESD22 STANDARD Method-A104

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF	VB	IR	VF	VB	IR
61	336.0mV	48.90V	110.2nA	336.0mV	47.19V	110.6nA
62	335.7mV	48.22V	111.1nA	337.1mV	47.86V	111.4nA
63	336.2mV	49.28V	107.3nA	335.9mV	48.92V	112.0nA
64	334.7mV	47.45V	111.9nA	334.7mV	48.43V	106.0nA
65	336.5mV	47.57V	107.3nA	335.5mV	47.45V	106.9nA
66	335.2mV	48.82V	105.7nA	337.4mV	47.99V	105.3nA
67	337.4mV	47.08V	105.4nA	334.8mV	47.51V	108.8nA
68	334.8mV	47.58V	107.2nA	334.9mV	46.99V	107.6nA
69	335.2mV	48.03V	104.8nA	337.5mV	47.23V	109.6nA
70	336.6mV	48.55V	109.1nA	337.3mV	47.87V	109.0nA
71	336.8mV	47.99V	109.6nA	336.4mV	48.19V	111.2nA
72	335.8mV	49.61V	110.2nA	337.0mV	48.47V	105.7nA
73	336.0mV	49.51V	106.6nA	335.1mV	48.76V	111.5nA
74	334.8mV	47.07V	106.5nA	337.4mV	47.10V	111.2nA
75	336.4mV	49.28V	106.9nA	334.6mV	49.61V	111.0nA
76	335.0mV	47.52V	110.7nA	336.9mV	47.25V	106.1nA
77	335.6mV	49.35V	109.8nA	335.0mV	47.45V	109.7nA

Made By: King Huang

Approval: Peter Yang



High Temperature High Humidity Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: 85±2°C, 85±5%RH, 1000Hrs

Test Date: 2016.03.14 ~ 2016.04.26

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF	VB	IR	VF	VB	IR
1	334.8mV	47.98V	105.1nA	336.5mV	47.62V	105.8nA
2	335.9mV	46.90V	105.6nA	334.6mV	46.99V	104.8nA
3	336.4mV	46.88V	106.7nA	337.4mV	47.91V	107.8nA
4	337.3mV	47.01V	111.9nA	337.3mV	49.32V	111.3nA
5	337.1mV	49.19V	110.7nA	337.1mV	48.80V	104.9nA
6	334.9mV	47.16V	111.2nA	336.3mV	47.50V	110.1nA
7	334.5mV	48.11V	111.3nA	337.2mV	47.11V	112.3nA
8	336.7mV	48.84V	111.1nA	335.2mV	47.11V	108.6nA
9	336.1mV	48.54V	106.1nA	337.2mV	48.84V	106.5nA
10	337.3mV	49.27V	107.8nA	335.9mV	48.80V	111.0nA
11	336.1mV	48.20V	109.1nA	335.6mV	48.58V	108.1nA
12	335.9mV	49.26V	107.8nA	336.0mV	48.91V	105.6nA
13	335.8mV	47.11V	108.0nA	336.5mV	48.76V	107.8nA
14	334.6mV	46.96V	106.0nA	336.1mV	47.94V	105.0nA
15	337.2mV	49.22V	112.0nA	334.8mV	47.81V	111.5nA
16	337.3mV	47.99V	111.0nA	335.1mV	47.96V	105.4nA
17	334.9mV	48.66V	106.5nA	335.4mV	47.32V	108.5nA
18	335.0mV	47.51V	106.0nA	337.0mV	49.64V	110.5nA
19	335.0mV	47.42V	105.3nA	336.3mV	48.94V	109.6nA
20	335.5mV	48.31V	109.2nA	335.5mV	47.67V	107.6nA
21	336.1mV	49.44V	106.9nA	334.8mV	47.69V	109.1nA
22	337.3mV	48.20V	111.7nA	337.3mV	46.94V	111.4nA
23	337.2mV	49.15V	111.3nA	336.8mV	48.15V	112.3nA
24	334.7mV	47.46V	109.2nA	336.7mV	49.27V	108.5nA
25	335.3mV	48.89V	111.0nA	335.8mV	49.08V	108.2nA
26	336.9mV	49.05V	110.8nA	334.7mV	48.12V	106.8nA
27	336.1mV	48.30V	104.9nA	336.6mV	48.71V	108.3nA
28	337.0mV	49.59V	110.1nA	335.3mV	47.76V	109.5nA
29	335.1mV	48.70V	106.4nA	335.6mV	49.43V	106.4nA
30	337.1mV	49.00V	107.7nA	336.6mV	48.60V	104.8nA



High Temperature High Humidity Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: 85±2°C, 85±5%RH, 1000Hrs

Test Date: 2016.03.14 ~ 2016.04.26

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF	VB	IR	VF	VB	IR
31	335.1mV	47.70V	104.7nA	337.1mV	48.34V	105.5nA
32	336.1mV	46.88V	108.1nA	336.4mV	47.94V	108.2nA
33	336.6mV	48.75V	104.9nA	336.3mV	48.61V	112.1nA
34	335.0mV	49.33V	105.7nA	336.0mV	47.90V	107.7nA
35	336.1mV	47.23V	107.5nA	335.9mV	48.64V	107.1nA
36	335.0mV	48.12V	108.5nA	334.8mV	47.65V	107.9nA
37	337.4mV	49.07V	108.7nA	337.0mV	49.65V	107.1nA
38	335.3mV	49.56V	105.2nA	336.9mV	47.17V	105.5nA
39	336.8mV	47.10V	106.3nA	336.0mV	49.27V	109.3nA
40	335.3mV	48.71V	109.9nA	335.0mV	47.31V	108.6nA
41	336.8mV	48.35V	112.4nA	337.1mV	47.31V	109.2nA
42	335.0mV	49.17V	111.3nA	334.8mV	49.45V	112.5nA
43	336.6mV	48.55V	110.5nA	336.0mV	49.42V	104.7nA
44	335.5mV	49.32V	108.4nA	335.5mV	49.40V	109.7nA
45	337.4mV	48.90V	111.8nA	335.6mV	47.27V	109.7nA
46	335.7mV	47.84V	106.5nA	334.5mV	49.29V	112.1nA
47	336.7mV	48.88V	108.6nA	336.6mV	49.05V	111.6nA
48	336.4mV	48.72V	108.9nA	335.1mV	48.32V	109.5nA
49	336.4mV	47.03V	110.8nA	334.5mV	47.60V	105.2nA
50	336.3mV	48.81V	108.3nA	335.2mV	47.91V	107.5nA
51	337.4mV	48.08V	111.9nA	334.8mV	48.56V	105.2nA
52	335.1mV	49.17V	110.1nA	336.2mV	46.99V	110.1nA
53	337.2mV	49.04V	105.3nA	335.2mV	48.74V	110.5nA
54	337.2mV	49.60V	107.2nA	335.9mV	47.75V	110.8nA
55	335.2mV	47.41V	104.7nA	336.9mV	47.05V	106.8nA
56	337.1mV	47.06V	105.9nA	336.8mV	47.19V	109.1nA
57	337.0mV	47.83V	111.7nA	336.2mV	49.53V	108.4nA
58	337.3mV	46.86V	106.9nA	336.2mV	47.35V	109.2nA
59	335.4mV	48.72V	106.1nA	335.5mV	49.64V	112.5nA
60	337.0mV	47.60V	106.3nA	335.9mV	49.52V	112.4nA



High Temperature High Humidity Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: 85±2°C, 85±5%RH, 1000Hrs

Test Date: 2016.03.14 ~ 2016.04.26

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF	VB	IR	VF	VB	IR
61	335.5mV	48.41V	111.3nA	336.0mV	48.86V	111.4nA
62	337.4mV	47.33V	112.3nA	336.7mV	47.33V	107.6nA
63	335.1mV	47.75V	110.3nA	335.7mV	48.98V	105.2nA
64	337.0mV	47.61V	112.4nA	336.7mV	48.02V	106.8nA
65	334.5mV	46.99V	104.8nA	337.1mV	48.59V	111.6nA
66	337.1mV	47.64V	110.5nA	337.2mV	49.12V	111.0nA
67	337.0mV	49.36V	112.5nA	334.6mV	49.47V	111.6nA
68	334.8mV	48.07V	109.5nA	336.9mV	46.92V	108.6nA
69	336.8mV	49.37V	111.3nA	336.2mV	47.80V	109.1nA
70	335.0mV	47.81V	112.0nA	337.1mV	47.62V	107.3nA
71	337.2mV	48.41V	104.9nA	335.5mV	46.99V	105.9nA
72	335.5mV	47.98V	105.7nA	336.9mV	49.44V	105.0nA
73	335.6mV	47.78V	107.8nA	335.3mV	49.01V	106.3nA
74	334.8mV	48.13V	107.6nA	337.3mV	47.85V	112.1nA
75	337.4mV	47.51V	108.7nA	335.7mV	47.97V	107.5nA
76	337.3mV	48.19V	109.8nA	335.8mV	49.08V	105.3nA
77	336.3mV	48.38V	111.2nA	337.2mV	47.77V	108.4nA

Made By: King Huang

Approval: Peter Yang



High Temper High Humidity Reverse Bies Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: 85±2°C, 85±5%RH, 80% VR, 1000Hrs

Test Date: 2016.03.14 ~ 2016.04.26

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF	VB	IR	VF	VB	IR
1	335.2mV	48.22V	109.0nA	336.3mV	48.01V	111.3nA
2	335.0mV	46.96V	106.2nA	336.4mV	47.76V	107.1nA
3	335.5mV	49.56V	104.6nA	337.2mV	49.01V	111.0nA
4	335.1mV	49.17V	112.2nA	336.7mV	48.48V	110.5nA
5	336.5mV	49.60V	106.8nA	336.0mV	48.46V	104.8nA
6	336.4mV	48.32V	107.3nA	336.9mV	48.48V	110.8nA
7	337.0mV	47.89V	105.6nA	337.1mV	49.65V	108.2nA
8	335.8mV	47.24V	106.4nA	336.7mV	47.21V	104.7nA
9	334.6mV	47.34V	110.7nA	335.1mV	48.31V	109.8nA
10	336.4mV	48.91V	108.6nA	335.4mV	49.32V	108.5nA
11	336.6mV	46.90V	110.0nA	335.5mV	47.53V	111.3nA
12	335.4mV	49.38V	109.5nA	335.4mV	49.47V	107.7nA
13	336.2mV	49.65V	105.6nA	336.2mV	48.21V	108.2nA
14	336.8mV	46.91V	105.4nA	335.3mV	47.75V	111.4nA
15	336.2mV	48.60V	109.5nA	336.0mV	48.10V	106.7nA
16	334.9mV	47.66V	109.5nA	335.9mV	49.06V	109.2nA
17	337.4mV	46.97V	110.5nA	335.9mV	47.29V	107.2nA
18	336.1mV	46.89V	108.6nA	335.1mV	47.15V	108.8nA
19	335.4mV	49.09V	105.6nA	337.1mV	49.28V	110.1nA
20	337.2mV	49.41V	112.0nA	336.5mV	47.50V	108.1nA
21	336.2mV	49.15V	110.5nA	334.6mV	47.02V	108.0nA
22	335.6mV	47.22V	107.8nA	337.4mV	48.85V	109.2nA
23	334.7mV	48.78V	108.5nA	335.9mV	47.63V	110.8nA
24	335.0mV	48.22V	106.9nA	336.6mV	47.21V	104.9nA
25	335.1mV	49.51V	107.4nA	335.5mV	47.91V	109.4nA
26	337.0mV	48.41V	108.8nA	336.9mV	48.99V	109.2nA
27	337.1mV	48.34V	105.3nA	337.2mV	49.20V	106.5nA
28	334.9mV	47.86V	108.7nA	334.5mV	48.62V	112.2nA
29	337.2mV	49.54V	110.0nA	334.5mV	49.62V	104.7nA
30	336.4mV	49.27V	111.0nA	336.6mV	48.13V	104.6nA



High Temper High Humidity Reverse Bies Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: 85±2°C, 85±5%RH, 80% VR, 1000Hrs

Test Date: 2016.03.14 ~ 2016.04.26

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF	VB	IR	VF	VB	IR
31	335.7mV	49.65V	111.6nA	334.6mV	49.23V	109.7nA
32	335.5mV	49.57V	109.6nA	337.2mV	48.88V	109.2nA
33	337.1mV	47.94V	107.8nA	337.3mV	47.01V	108.8nA
34	337.5mV	47.44V	109.0nA	337.1mV	47.64V	108.2nA
35	335.5mV	46.99V	106.2nA	337.2mV	47.43V	107.5nA
36	335.4mV	48.41V	107.0nA	334.6mV	48.33V	112.0nA
37	336.1mV	47.43V	106.9nA	335.7mV	48.78V	112.1nA
38	336.2mV	48.32V	109.7nA	337.5mV	49.52V	111.8nA
39	335.3mV	48.51V	107.2nA	336.2mV	47.07V	112.4nA
40	336.9mV	48.45V	110.6nA	336.4mV	46.95V	108.6nA
41	337.2mV	47.79V	110.0nA	336.0mV	49.22V	108.9nA
42	336.6mV	47.12V	107.6nA	335.7mV	48.89V	108.8nA
43	335.0mV	49.54V	105.5nA	337.5mV	49.51V	108.1nA
44	335.2mV	47.12V	106.7nA	334.6mV	49.09V	106.0nA
45	336.2mV	47.87V	105.7nA	335.9mV	48.68V	108.6nA
46	334.5mV	47.11V	112.2nA	335.7mV	48.96V	110.8nA
47	336.9mV	48.20V	110.6nA	335.8mV	47.91V	106.3nA
48	335.9mV	49.61V	110.0nA	335.1mV	49.26V	105.1nA
49	337.0mV	49.16V	112.1nA	334.8mV	48.29V	106.5nA
50	337.3mV	47.33V	110.4nA	335.5mV	48.23V	109.0nA
51	337.1mV	47.81V	111.5nA	335.5mV	48.33V	109.7nA
52	337.0mV	47.76V	106.4nA	335.2mV	48.49V	107.4nA
53	334.8mV	48.00V	111.4nA	335.8mV	47.65V	105.2nA
54	335.8mV	48.00V	108.3nA	336.1mV	48.17V	106.5nA
55	336.9mV	48.81V	106.6nA	337.1mV	48.02V	105.1nA
56	337.4mV	48.14V	111.7nA	337.5mV	47.78V	112.1nA
57	335.9mV	49.04V	107.2nA	335.3mV	47.50V	108.2nA
58	337.1mV	48.67V	106.3nA	337.5mV	47.61V	105.1nA
59	337.3mV	47.98V	109.4nA	335.1mV	48.84V	109.1nA
60	334.7mV	49.33V	106.3nA	337.5mV	47.58V	107.1nA



High Temper High Humidity Reverse Bies Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: 85±2°C, 85±5%RH, 80% VR, 1000Hrs

Test Date: 2016.03.14 ~ 2016.04.26

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF	VB	IR	VF	VB	IR
61	336.4mV	48.21V	106.7nA	335.8mV	47.22V	111.3nA
62	335.6mV	47.66V	108.6nA	334.9mV	46.98V	109.1nA
63	336.6mV	48.47V	105.8nA	335.3mV	49.20V	108.1nA
64	334.6mV	47.80V	106.4nA	336.6mV	48.00V	111.0nA
65	336.0mV	47.65V	106.3nA	334.5mV	47.49V	111.2nA
66	335.9mV	47.55V	107.3nA	334.9mV	48.63V	108.2nA
67	335.0mV	48.72V	107.8nA	334.8mV	47.22V	109.3nA
68	336.7mV	49.52V	108.4nA	334.8mV	48.73V	107.8nA
69	337.1mV	47.98V	105.0nA	336.0mV	48.42V	111.5nA
70	337.2mV	48.70V	112.3nA	335.0mV	48.48V	109.9nA
71	334.6mV	49.64V	111.0nA	334.7mV	47.72V	108.5nA
72	334.5mV	47.92V	111.1nA	336.8mV	47.62V	112.3nA
73	337.3mV	48.59V	112.5nA	337.1mV	47.57V	105.8nA
74	335.4mV	48.32V	106.4nA	336.7mV	49.12V	109.1nA
75	336.5mV	47.08V	105.6nA	337.3mV	48.67V	108.2nA
76	336.3mV	49.56V	110.1nA	337.4mV	48.12V	109.0nA
77	335.3mV	47.88V	108.7nA	335.4mV	47.77V	105.1nA

Made By: King Huang

Approval: Peter Yang



SeCoS Corporation

Solderability Test Data

Report No : T160429-011

Part No : SCS751V-40

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<370mV@IF=1mA, VB>40V@IR=1mA, IR<0.5uA@VR=30V

Test Condition: 245°C ± 5°C, 5Sec

Test Date: 2016.04.28

Test Standard : JESD22 STANDER Method-B102

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF	VB	IR	VF	VB	IR
1	335.0mV	47.66V	108.2nA	336.9mV	48.40V	105.5nA
2	334.6mV	47.12V	112.1nA	335.8mV	48.38V	110.2nA
3	336.5mV	48.57V	111.7nA	336.5mV	47.74V	109.3nA
4	334.8mV	48.55V	108.7nA	336.1mV	49.58V	111.1nA
5	337.1mV	47.92V	105.7nA	336.2mV	47.37V	106.8nA
6	337.3mV	47.74V	108.1nA	336.2mV	48.44V	109.2nA
7	335.7mV	48.77V	107.3nA	337.2mV	48.38V	107.6nA
8	336.4mV	49.53V	111.2nA	334.5mV	49.10V	106.8nA
9	334.9mV	48.73V	105.6nA	337.4mV	47.52V	107.5nA
10	334.6mV	48.01V	111.9nA	335.1mV	47.31V	111.6nA

Made By: King Huang

Approval: Peter Yang